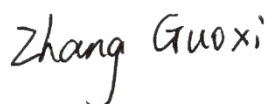


TEST REPORT

Applicant: XPPEN Technology CO.
Address: 15350 FAIRFIELD RANCH RD #G CHINO HILLS,
CA 91709 USA
Equipment Type: Magic Pro 13
Model Name: MDP1311 (refer to section 2.3)
Brand Name: XPPen
FCC ID: 2AKDT-MDP1311
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: Jun. 12, 2026
Test Date: Jun. 17, 2026 – Jun. 26, 2026
Date of Issue: Aug. 07, 2026

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

**Tested by:** Zhang Guoxi**Checked by:** Zong Liyao**Approved by:** Liao Jianming
(Technical Director)

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Aug. 07, 2026</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	601, Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☐ Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen, Guangdong
	☒ 1/F., Building B, Ganghongji High-Tech Intelligent Industrial Park, No.1008, Songbai Road, Yangguang Community, Xili Subdistrict, Nanshan District, Shenzhen, Guangdong
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196. The certification body is American Association for Laboratory Accreditation (A2LA).

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	XPPEN Technology CO.
Address	15350 FAIRFIELD RANCH RD #G CHINO HILLS, CA 91709 USA

2.2 Manufacturer Information

Manufacturer	Hanvon Ugee Technology Co., Ltd.
Address	18/F, 19/F, 20/F, No.1 Bldg., Longhua Digital Intelligent Manufacturing Center, No. 238 Longsheng Road, Longhua District, Shenzhen

2.3 General Description for Equipment under Test (EUT)

EUT Name	Magic Pro 13
Model Name Under Test	MDP1311
Series Model Name	MDP1312, MDP1313, MDP1314, MDP1315
Description of Model name differentiation	All models are same with electrical parameters and internal circuit structure, but only differ in model name. (This information provided by the customer)
Hardware Version	N/A
Software Version	N/A
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Ancillary Equipment 1	Battery	
	Brand Name	/
	Model No.	HQ-8613VK
	Serial No.	N/A
	Capacitance	Rated: 9820mAh Typical: 10200mAh
	Rated Voltage	3.91V
	Limited Voltage	4.5V
	Manufacturer	Dongguan Veken Battery Co., Ltd.
Ancillary Equipment 2	USB Cable	
	Model No.	/
	Length (Approx.)	1.5m
Ancillary Equipment 3	Stylus Pen	
	Model No.	/

2.5 Technical Information

Network and Wireless connectivity	Bluetooth (BR+EDR+BLE) WIFI 802.11a, 802.11b, 802.11g, 802.11n(HT20/40), 802.11ac(VHT20/40/80/160), 802.11ax(HE20/40/80/160)
Classification of equipment	Class B

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=2$.

Measurement	Value
Conducted emissions (9 kHz-150 kHz)	3.36 dB
Conducted emissions (150 kHz-30 MHz)	2.92 dB
Radiated emissions (9 kHz-30 MHz)	3.78 dB
Radiated emissions (30 MHz-1 GHz)	4.24 dB
Radiated emissions (1 GHz-6 GHz)	5.10 dB
Radiated emissions (6 GHz-18 GHz)	5.30 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
WIFI Router	ASUS	ROG Rapture GT-BE98 Pro	N/A	N/A	N/A	☒
Bluetooth Earphone	SAMSUNG	Gear Circle	N/A	N/A	N/A	☒
Type-C Earphone	OPPO	MH156	N/A	1.12m	N/A	☒
Laptop	Lenovo	N/A	N/A	N/A	N/A	☒
Data connector	HBR	Type-C to USB 3.0	N/A	N/A	N/A	☒
USB disk	Sandisk	CZ73-32G	N/A	N/A	32G	☒
Type-C To DP Cable	N/A	N/A	N/A	N/A	N/A	☒
Monitor	AOC	N/A	N/A	N/A	N/A	☒
Keyboard	N/A	N/A	N/A	N/A	N/A	☒
Adapter	N/A	N/A	N/A	N/A	N/A	☒

4.2 Test Configurations

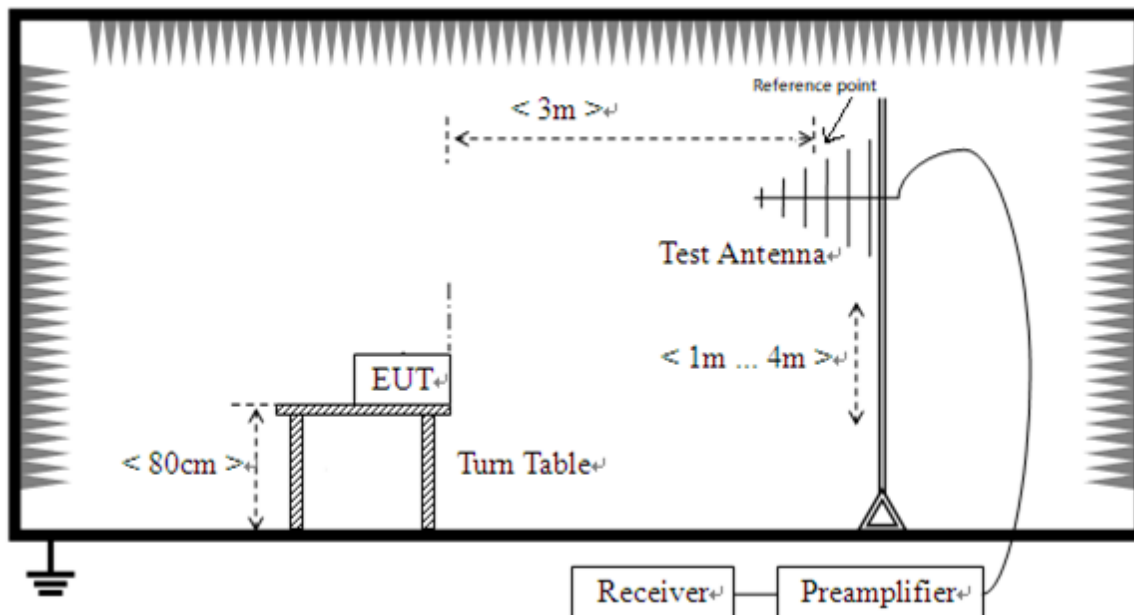
All test modes of EUT are listed in the table below.

Test Mode Configuration	Description
Mode 1	<u>The H-Pattern Test Mode</u> EUT + Adapter + USB Cable + Battery + Keyboard + Capacitive stylus + TF Card
Mode 2	<u>The Type-C Earphone Test Mode</u> EUT + Adapter + USB Cable + Battery + Keyboard + Capacitive stylus + Color Bar(1Khz Tone) + Type-C Earphone
Mode 3	<u>The DP Test Mode</u> EUT + Adapter + USB Cable + Battery + Keyboard + Capacitive stylus + Color Bar(1Khz Tone) + Type-C To DP Cable + Monitor
Mode 4	<u>The Rear Camera Test Mode</u> EUT + Adapter + USB Cable + Battery + Keyboard + Capacitive stylus + TF Card + Rear Camera
Mode 5	<u>The Front Camera Test Mode</u> EUT + Adapter + USB Cable + Battery + Keyboard + Capacitive stylus + TF Card + Front Camera
Mode 6	<u>USB Data Transmission Test Mode</u> EUT + USB Cable + Battery + Keyboard + Capacitive stylus + Laptop + TF Card
Mode 7	<u>OTG Data Transmission Test Mode</u> EUT + Battery + Data connector + USB disk + TF Card

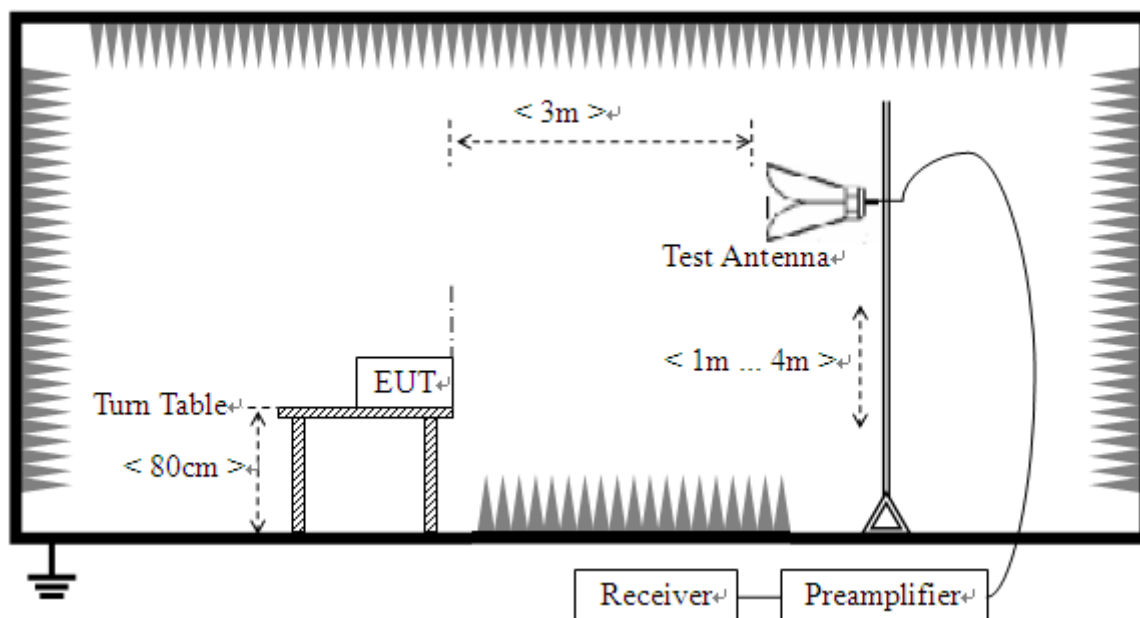
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 7	1
Conducted Emission, AC Ports	Mode 1~Mode 6	1
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

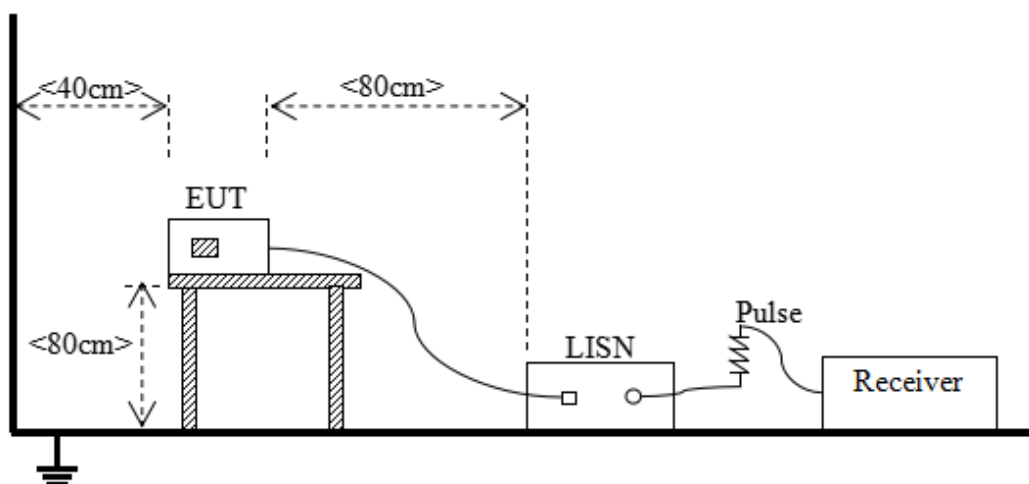
Test Setup 1



Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2

Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)	Field Strength Average (dB $\mu\text{V/m}$)	Field Strength Peak (dB $\mu\text{V/m}$)
1 - F_M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M , in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:

$$L_{3m} = L_{10m} + 20 \cdot \log(d_{10m}/d_{3m})$$
Where:
 L_{3m} is Average Class A limit at 3m;
 L_{10m} is Average Class A limit at 10m;
 d_{10m} is Measurement distance in 10m;
 d_{3m} is Measurement distance in 3m.
For this case: $L_{3m} = 49.5 + 20 \cdot \log(10/3) = 60$ (dB $\mu\text{V/m}$).

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108 \text{ MHz}$	1 GHz
$108 \text{ MHz} \leq F_X \leq 500 \text{ MHz}$	2 GHz
$500 \text{ MHz} \leq F_X \leq 1 \text{ GHz}$	5 GHz
$F_X \geq 1 \text{ GHz}$	$5 * F_X$ or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360° , and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dBμV) = Reading (dBμV) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

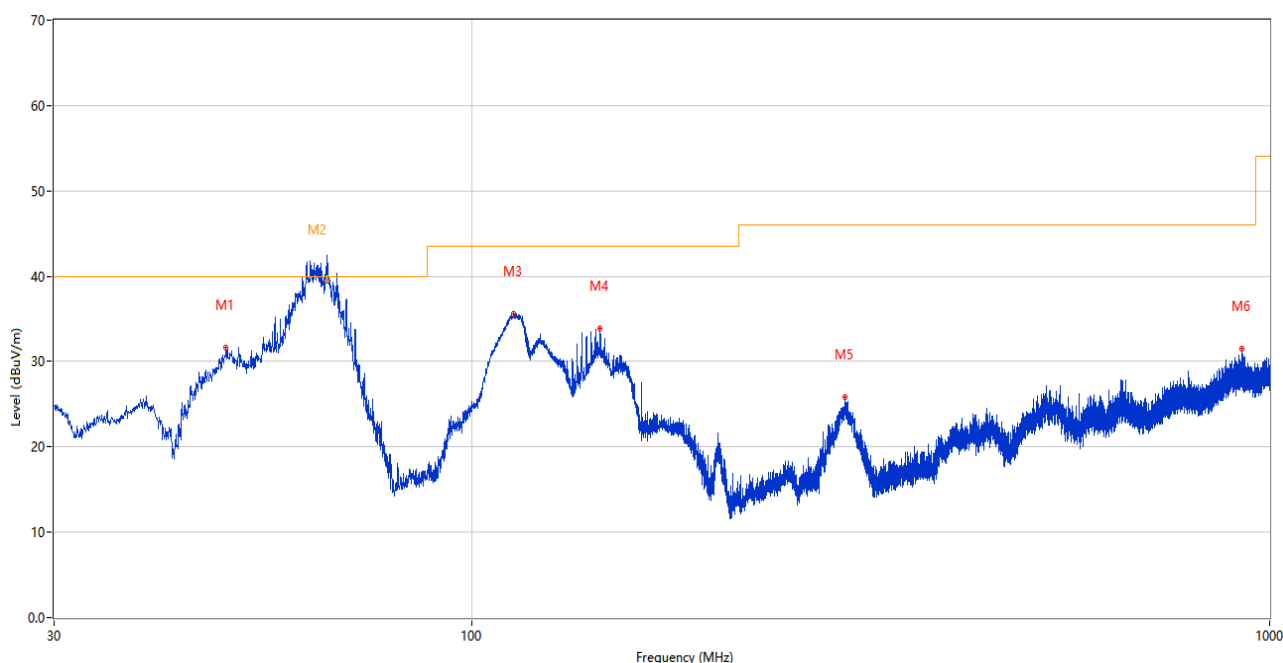
A.1 Radiated Emission

Note: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Sample No.	S14	Temperature	21.5°C
Humidity	51%RH	Pressure	99.7kPa
Test Engineer	Ye Xuanwei	Test Date	2026.06.26

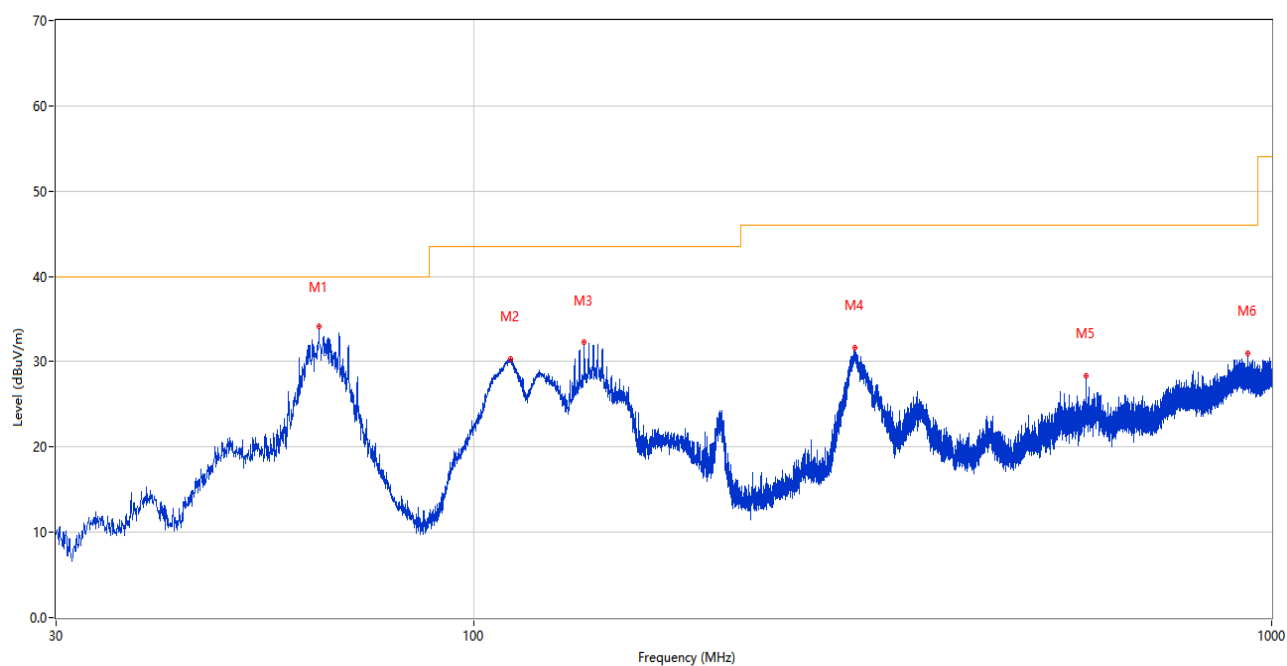
Test Mode 1

1) Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	49.206	31.58	-25.24	40.0	8.42	Peak	303.00	100	Vertical	Pass
2	65.992	43.60	-27.47	40.0	-3.60	Peak	53.00	101	Vertical	N/A
2*	65.992	39.47	-27.47	40.0	0.53	QP	53.00	101	Vertical	Pass
3	112.789	35.60	-26.83	43.5	7.90	Peak	260.00	100	Vertical	Pass
4	144.945	33.84	-29.80	43.5	9.66	Peak	28.00	100	Vertical	Pass
5	293.791	25.81	-23.26	46.0	20.19	Peak	303.00	100	Vertical	Pass
6	922.740	31.51	-8.60	46.0	14.49	Peak	208.00	200	Vertical	Pass

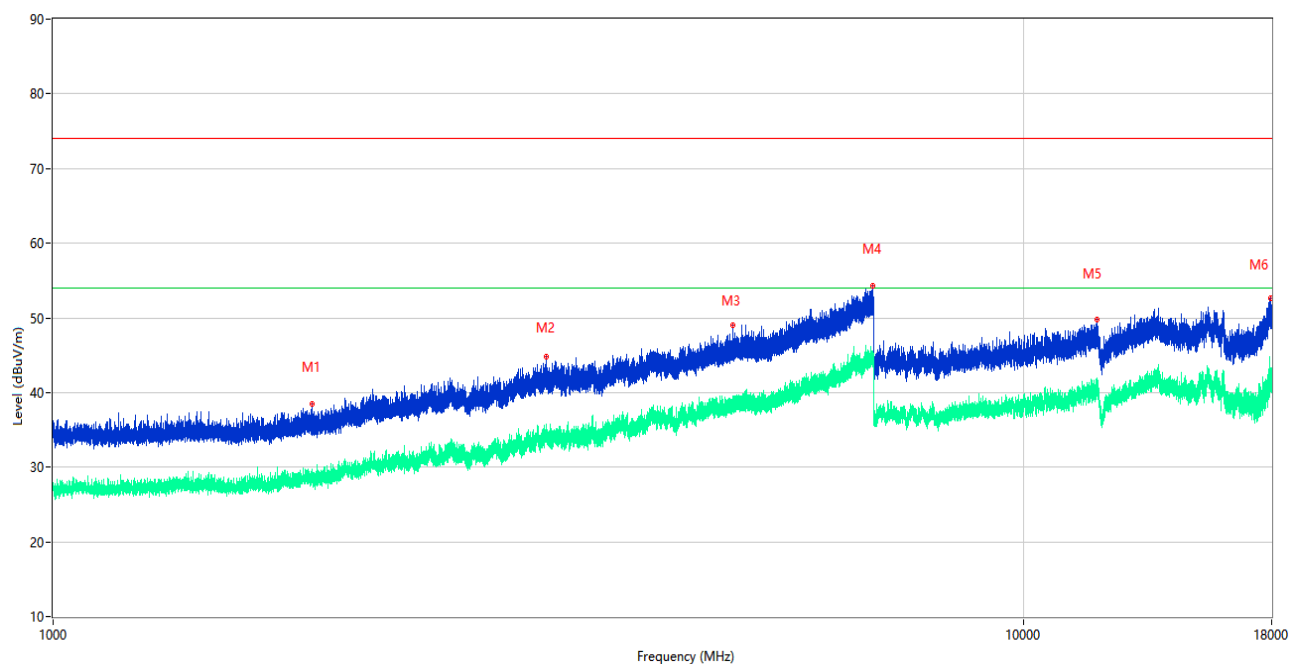
2) Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	64.095	34.09	-26.98	40.0	5.91	Peak	334.00	100	Horizontal	Pass
2	111.383	30.33	-26.59	43.5	13.17	Peak	119.00	100	Horizontal	Pass
3	137.573	32.24	-29.73	43.5	11.26	Peak	94.00	100	Horizontal	Pass
4	300.339	31.65	-23.37	46.0	14.35	Peak	75.00	100	Horizontal	Pass
5	584.889	28.32	-15.92	46.0	17.68	Peak	90.00	200	Horizontal	Pass
6	934.234	31.02	-8.60	46.0	14.98	Peak	187.00	200	Horizontal	Pass

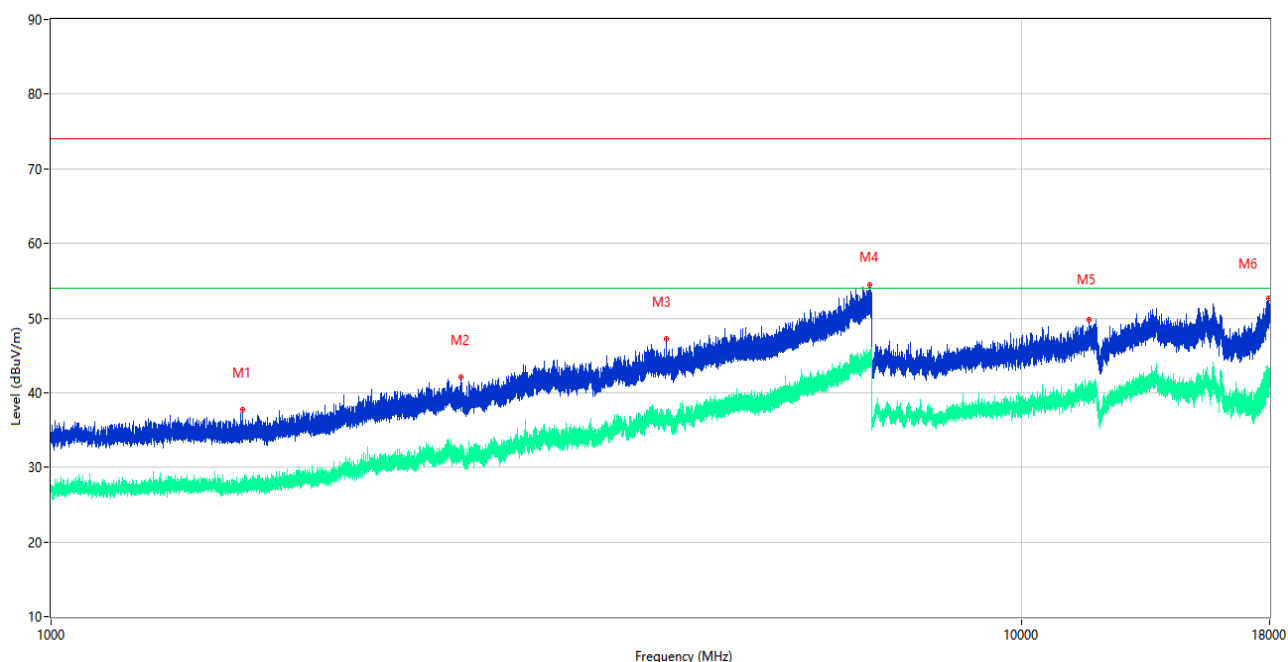
Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Below 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Bi-Log	SCHWARZB ECK	VULB 9163	01414	2023.11.03	2026.11.02	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

3) Test Antenna Vertical, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1847.080	38.48	-17.25	74.0	35.52	Peak	360.00	100	Vertical	Pass
1**	1847.080	28.73	-17.25	54.0	25.27	AV	360.00	100	Vertical	Pass
2	3218.580	44.76	-9.07	74.0	29.24	Peak	196.00	100	Vertical	Pass
2**	3218.580	33.64	-9.07	54.0	20.36	AV	196.00	100	Vertical	Pass
3	5018.650	49.03	-4.16	74.0	24.97	Peak	163.00	100	Vertical	Pass
3**	5018.650	37.97	-4.16	54.0	16.03	AV	163.00	100	Vertical	Pass
4	6990.990	54.34	0.83	74.0	19.66	Peak	298.00	100	Vertical	Pass
4**	6990.990	43.91	0.83	54.0	10.09	AV	298.00	100	Vertical	Pass
5	11893.349	49.82	5.57	74.0	24.18	Peak	360.00	100	Vertical	Pass
5**	11893.349	40.41	5.57	54.0	13.59	AV	360.00	100	Vertical	Pass
6	17975.251	52.68	10.00	74.0	21.32	Peak	134.00	100	Vertical	Pass
6**	17975.251	43.36	10.00	54.0	10.64	AV	134.00	100	Vertical	Pass

4) Test Antenna Horizontal, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1574.860	37.76	-17.94	74.0	36.24	Peak	147.00	100	Horizontal	Pass
1**	1574.860	27.79	-17.94	54.0	26.21	AV	147.00	100	Horizontal	Pass
2	2641.380	42.13	-12.33	74.0	31.87	Peak	358.00	100	Horizontal	Pass
2**	2641.380	32.33	-12.33	54.0	21.67	AV	358.00	100	Horizontal	Pass
3	4300.740	47.25	-5.49	74.0	26.75	Peak	0.00	100	Horizontal	Pass
3**	4300.740	37.26	-5.49	54.0	16.74	AV	0.00	100	Horizontal	Pass
4	6964.640	54.39	0.61	74.0	19.61	Peak	200.00	100	Horizontal	Pass
4**	6964.640	44.40	0.61	54.0	9.60	AV	200.00	100	Horizontal	Pass
5	11741.550	49.75	5.60	74.0	24.25	Peak	198.00	100	Horizontal	Pass
5**	11741.550	40.81	5.60	54.0	13.19	AV	198.00	100	Horizontal	Pass
6	17976.900	52.57	9.98	74.0	21.43	Peak	232.00	100	Horizontal	Pass
6**	17976.900	42.12	9.98	54.0	11.88	AV	232.00	100	Horizontal	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Above 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Horn	SCHWARZB ECK	BBHA 9120D	02459	2023.10.26	2026.10.25	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

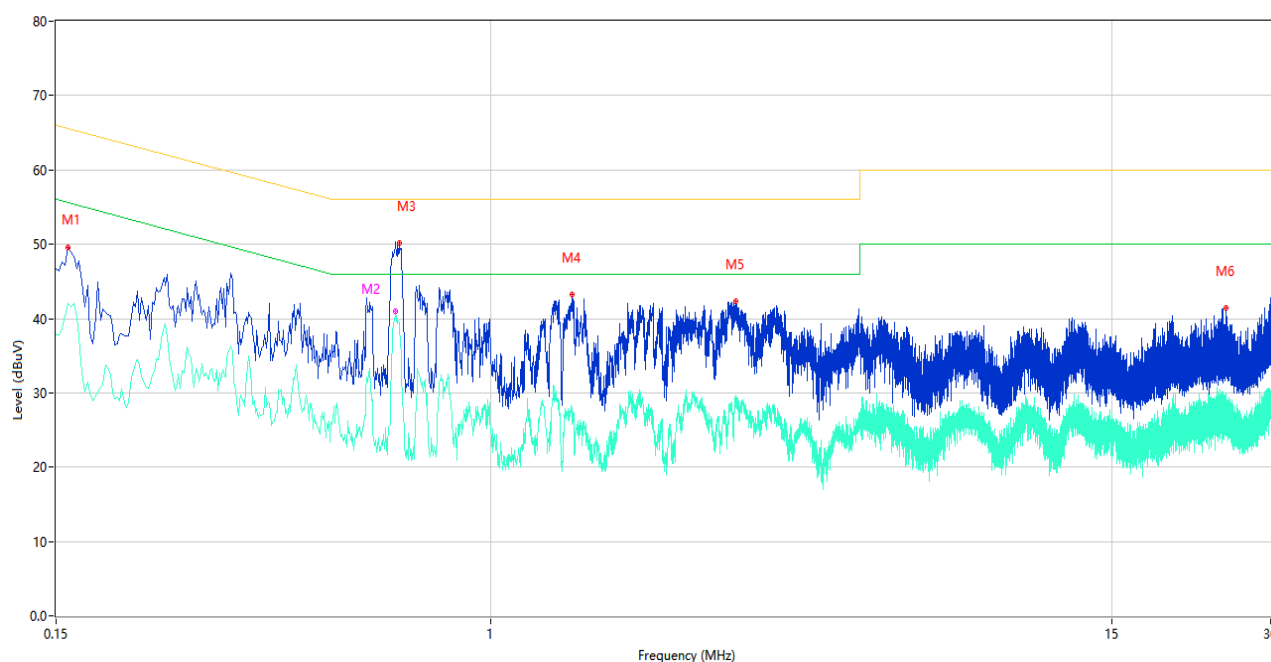
A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Sample No.	S14	Temperature	22.6°C
Humidity	51%RH	Pressure	100.1kPa
Test Engineer	Tang Xuming	Test Date	2026.06.17

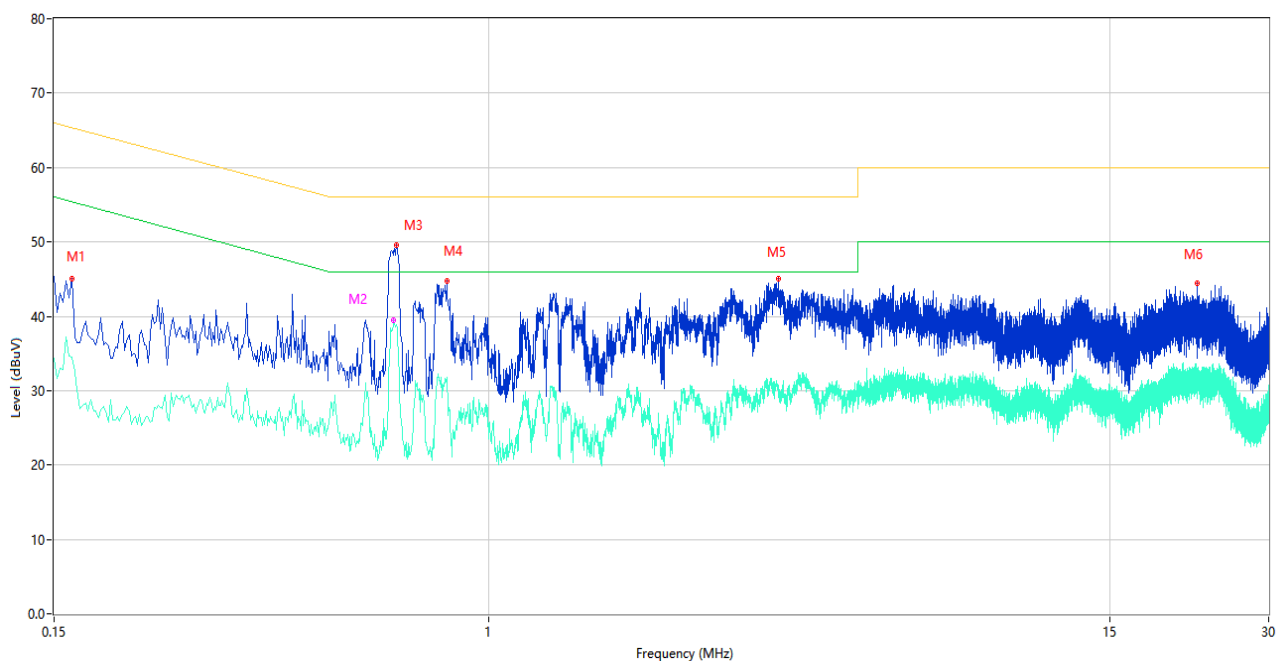
Test Mode 1

1) AC Ports - L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.158	49.59	10.27	65.57	15.98	Peak	L	Pass
1**	0.158	42.07	10.27	55.57	13.50	AV	L	Pass
2	0.660	50.37	10.26	56.00	5.63	Peak	L	Pass
2**	0.660	40.95	10.26	46.00	5.05	AV	L	Pass
3	0.670	50.16	10.26	56.00	5.84	Peak	L	Pass
3**	0.670	39.53	10.26	46.00	6.47	AV	L	Pass
4	1.426	43.16	10.34	56.00	12.84	Peak	L	Pass
4**	1.426	27.96	10.34	46.00	18.04	AV	L	Pass
5	2.910	42.37	10.50	56.00	13.63	Peak	L	Pass
5**	2.910	28.00	10.50	46.00	18.00	AV	L	Pass
6	24.720	41.44	15.25	60.00	18.56	Peak	L	Pass
6**	24.720	26.38	15.25	50.00	23.62	AV	L	Pass

2) AC Ports - N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.162	45.04	10.17	65.36	20.32	Peak	N	Pass
1**	0.162	34.45	10.17	55.36	20.91	AV	N	Pass
2	0.660	48.72	10.18	56.00	7.28	Peak	N	Pass
2**	0.660	39.42	10.18	46.00	6.58	AV	N	Pass
3	0.668	49.58	10.18	56.00	6.42	Peak	N	Pass
3**	0.668	38.90	10.18	46.00	7.10	AV	N	Pass
4	0.832	44.71	10.19	56.00	11.29	Peak	N	Pass
4**	0.832	31.76	10.19	46.00	14.24	AV	N	Pass
5	3.530	45.08	10.48	56.00	10.92	Peak	N	Pass
5**	3.530	30.41	10.48	46.00	15.59	AV	N	Pass
6	21.974	44.43	14.74	60.00	15.57	Peak	N	Pass
6**	21.974	32.15	14.74	50.00	17.85	AV	N	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9038B	MY61380132	2025.12.26	2026.12.25	☒
LISN	SCHWARZB ECK	NSLK 8127	01009	2025.07.15	2026.07.14	☒
LISN	SCHWARZB ECK	NNBM8124	8124-510	2026.01.21	2027.01.20	☐
LISN	SCHWARZB ECK	NNBM8124	8124-509	2026.01.21	2027.01.20	☐
Shielded Room	YiHeng Electronic Co., Ltd	/	235	2024.11.05	2027.11.04	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

ANNEX B TEST SETUP PHOTOS

Please refer the document “Ti-CC26060266-AE-1.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “Ti-CC26060266-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “Ti-CC26060266-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
2. The report without China inspection body and laboratory Mandatory Approval (CMA) mark has no effect of proving to the society.
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4. This report is invalid if it is altered, without the signature of the testing and approval personnel, or without the "inspection and testing dedicated stamp" or test report stamp.
5. The test data and results are only valid for the tested samples provided by the customer.
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--END OF REPORT--